

cleanliness control

Introducing the new standard in surface particle contamination measurements

Erik Vermeulen, CEO Fastmicro 7th June 2023

Introducing Fastmicro

Facts

10 START team members 2019 founded 16 36 end-clients globally scanners 20 built service & aftersales contracts

Presence



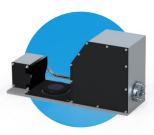
Core product portfolio



Sample **Scanner**







Fallout Scanner

Clients





















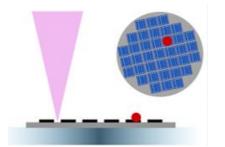




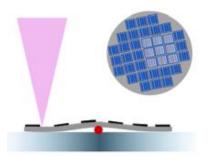
At least a EUR 30 billion yield loss annually in semiconductors due to particle contamination, driving the need for ultra cleanliness

Effects of contamination on semiconductor wafers

Wafer front side



Wafer back side



→ CD



(visual representation)

Side-effects:

- Non-functional die where the particle is located (front side)
- Overlay/focus errors and wafer and clamp damage (back side)

Cost of yield

(Output loss; Uptime Loss; Rework; Recalls)

EUR 590 B, CAGR 9,2%

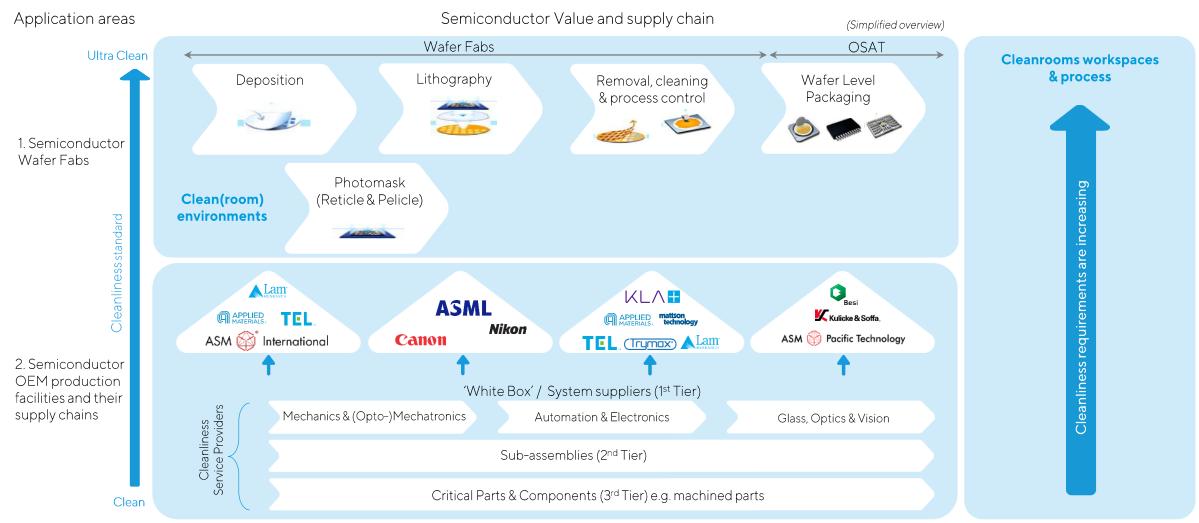
semiconductor revenue

~ EUR 75 B (12.5%)¹ production related yield loss

~ EUR 30 B (37.5%)² related to particle contamination

- 1. Mid point between the estimated range of 5% to 20%. Sources: <u>link 1</u>, <u>link 2</u>, company estimates
- 2. Mid point between the estimated range of 25% to 50%. Sources: link 3, link 4

fastmcro Why now: cleanliness is now required everywhere in the semiconductor value & supply chain



Current particle counting metrology slow & not effective enough

Application areas

Semiconductor Value and supply chain

(Simplified overview)

Ultra Clean

Slow

Expensive

Cleanrooms workspaces & Process

A clean room is not a clean product

• Sensitivity too high

1. Semiconductor Wafer Fabs ('Nanometers')

OEM and supply chain (micrometers)

Wafer & display production (nanometers)

Subjectivity

Statically challenged with higher sensitivity Need for a manufacturing metrology solution with high throughput & objectivity



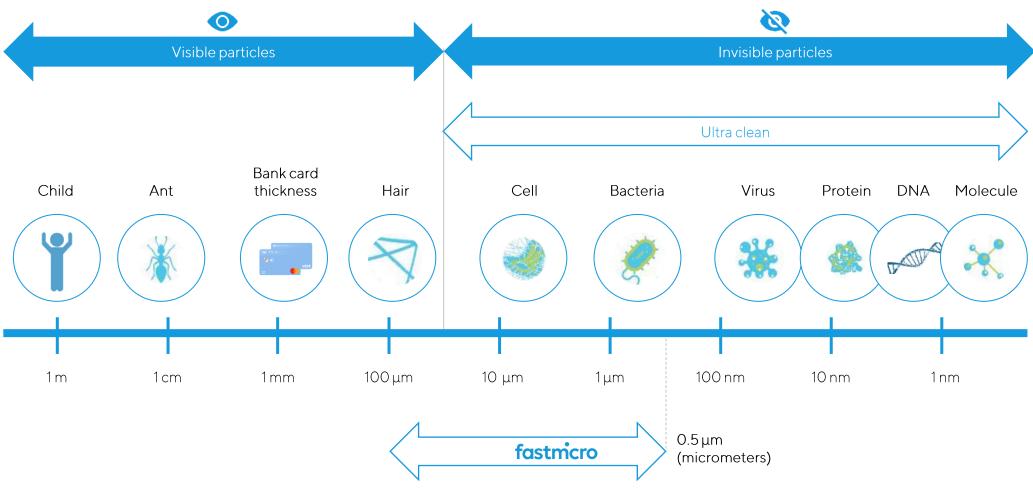


facilities and their supply chains ('Micrometers')

2. Semiconductor OEM production

Clean

High Volume Manufacturing environments have to control particles invisible to the human eye



Source: Long-term measurement of ultrafine particles in the Urban and Rural Environment; Dirk Felton, P.E. Research Scientist III

Fastmicro: The IoT sensor for surface particle contamination in the digital factory of the future

Integrated metrology solution:

hardware + software + services

Current practices

Desired industry standard

Particle measurement method





Airborne Particles Counters

Liquid Particles Counters



Surface Particles Counters

Key Persona



Lab Scientist

Factory Operator

Cleanliness process engineers' journey from interviews in the supply chain





Airborne Particles Counters



From ISO 7-> 5
With airborne particle counters.

Cleanliness process engineers' journey from interviews in the supply chain



Airborne Particles Counters



From ISO 7-> 5
With airborne particle counters.

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Surface Particles Counters

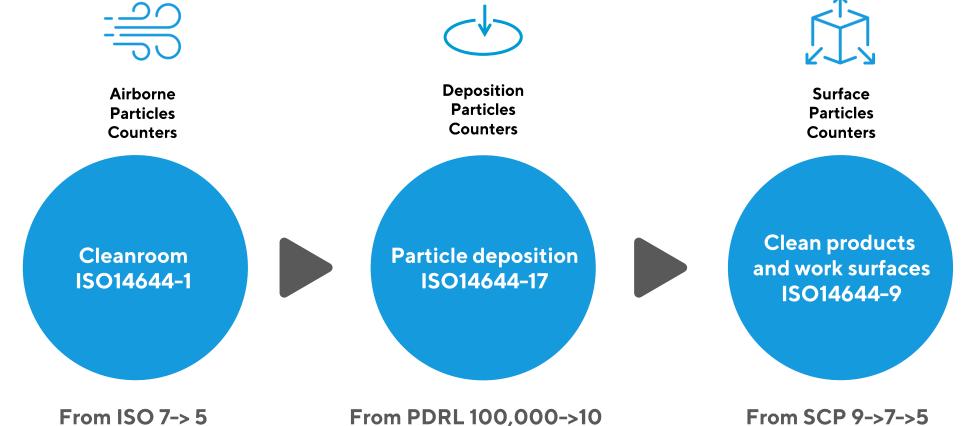
Clean products and work surfaces ISO14644-9

From SCP 9->7->5

from UV / bright light lamp to lab based equipment to tape lifting with scatterometry.

Cleanliness process engineers' journey from interviews in the supply chain



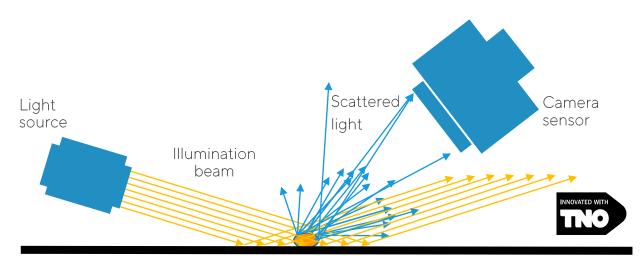


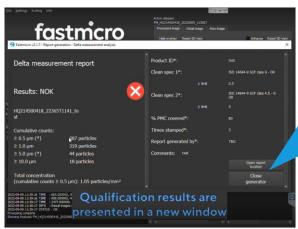
From SCP 9->7->5

from UV / bright light lamp to lab based equipment to tape lifting with scatterometry.

With airborne particle counters.

fastmicro Unique and patent-protected technology set-up using scattered light to detect surface particles at microscale





Operator independent processing and reporting of cleanliness results according to regulatory standards

Design principles:







Size calibration on PSL shape & optical properties, according to the NIST standard



Smart inspection of particles of interest to improve cleanliness strategy

Service offer building blocks

Preventive maintenance & calibration To secure (synchronised) performance On-site repair SLA Fast response time (5 days)

Benefits Fastmicro measurements at microscale



Fast

Imaging in seconds



Quantitative

Measurement and qualification reports



Easy to operate

Operator independent



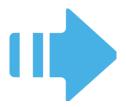
Accurate

High-resolution measurement (quantity, position, size)



Consistent

Objective measurements, time after time



High throughput

Processing in less than a minute

fastmicro Product offering covering the entire semiconductor value & supply chain

Sample Scanner



Applications:







Parts



Cleaning

Product Scanner



Applications:



and back



Reticle, photomask

back



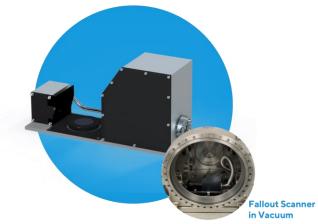


Wafer back / 3Di e.g. copper to

blanks / bevels copper bonding



Fallout Scanner



Applications:







Cleanrooms

Workspace surface

Semiconductor & value chain focus area:

Wafer & display production

Semiconductor & value chain focus area:

Cleanrooms workspaces &

Semiconductor & value chain focus area:

OEM and supply chain

Particle Fallout Scanner for continuous monitoring of particle deposition in ambient or vacuum

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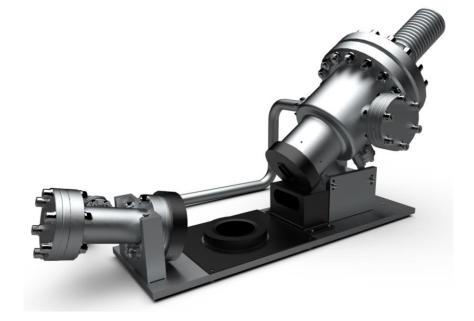




Easy to operateOperator
independent



Accurate
High-resolution
measurement
(quantity, position, size)





Consistent
Objective
measurements,
time after time

Industry leader semicon litho supports our core technology



Fastmicro has transformed our inspection capability business significantly. Before migration to this new inspection tool, we saw a 50% variation in the particle count measurements. This is now reduced to less than 10% in combination with a particle detection limit that went down significantly by more than one order of magnitude to 0.5 micrometer. We have confidence in the Fastmicro scanner to help us with finding an excellent quantification of the surface cleanliness of critical parts.

As valued customer, I know that the integration of Fastmicro, has allowed us to reach our required machine defectivity performance.

Besides **accurate measurements**, the tool offers **ease of use** and **high throughput** features. We appreciate the **professional service and collaboration** with Fastmicro to extend the capabilities of the tool further in the future.

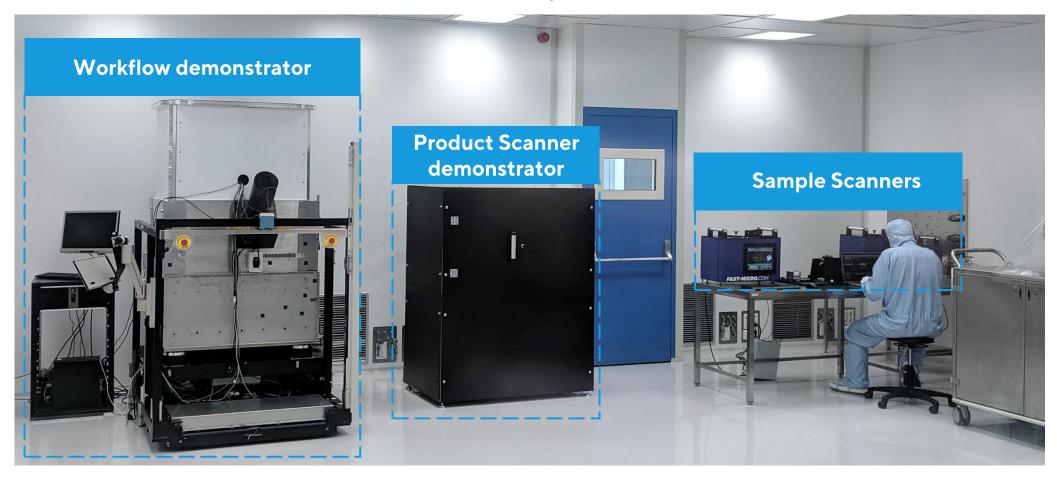
Dr. Ir. L.H.A. Leunissen ASML, cleanliness project manager





Demo lab for product development and customers testing

Fastmicro cleanroom in Geldrop, the Netherlands









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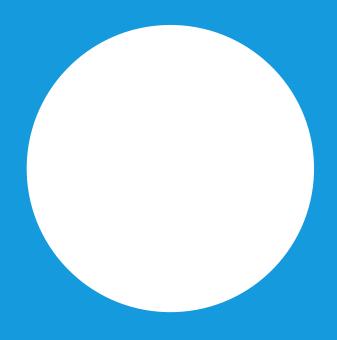
Dutch-Taiwan collaboration

- Leadinway partnership for regional expertise and service
- Innovations of Fastmicro to benefit sustainability through yield improvement in Taiwan (and China)
- In micro technology, with focus on semicon and display





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cleanliness control

Taiwan summary
September 2022

2022: 3 days quarrantine, masks and checks





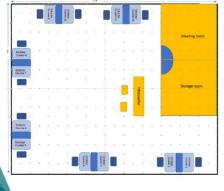
fastmicro Tradeshow





SILICON EUROPE JOINT BOOTH

BOOTH VISUALISATION:









Fab visit





Our business partner





